Short biographical note

Peter Mueller joined IBM Research as a Research Staff Member in 1988. His research expertise covers a broad range of areas from nanoscience to device physics, simulation, and computer technology. In nanoscience, his main experience is in the fields of scanning tunneling microscopy (STM) and atomic force microscopy (AFM), including specialized techniques such as z-V spectroscopy, STM-induced luminescence (STL) and STM-excited cathodoluminescence, in ultrahigh vacuum (UHV) or an electrochemical environment. Much of his experimental work has been carried out on organic materials, using highly customized instrumentation.
He also served as government counsel and as program chair in international conferences and workshops. He is member of the Electrochemical Society (ECS), the Swiss Physical Society (SPS), and IEEE.